

Notice of References Cited	Application/Control No. 10/764,734		Applicant(s)/Patent Under Reexamination CHANG, AO YU	
	Examiner Bena Miller		Art Unit 3725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,622,763	09-2003	Chen, Chin-Yu	144/350
*	B	US-6,098,680	08-2000	Nien, Ming	144/380
*	C	US-5,976,644	11-1999	Sanaee et al.	428/17
*	D	US-5,972,467	10-1999	Washo, Kenji	428/107
*	E	US-5,098,762	03-1992	Nakajima, Tsutomu	428/106
*	F	US-4,810,551	03-1989	Chu, Alan C.	428/106
*	G	US-5,972,467	10-1999	Washo, Kenji	428/107
*	H	US-5,456,964	10-1995	Tamura et al.	428/105
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 07229237 A	08-1995	Japan	INOUE et al.	E04C 02/12
	O	JP 09024505 A	01-1997	Japan	HASHIMOTO, TAKASHI	B27J 01/00
	P	JP 10113914 A	05-1998	Japan	HOSHIKAWA et al.	B27N 03/02
	Q	JP 2002173796 A	06-2002	Japan	HONG et al.	C25D 07/12
	R	JP 11346652 A	12-1999	Japan	KIMURA et al.	A23D 09/00
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.